HS-OP470ARH

Radiation Hardened, Very Low Noise **Quad Operational Amplifier**

February 1998

Features

- QML Qualified Per MIL-PRF-38535 Requirements
- Radiation Environment
 - Total Dose 1 x 10⁵ RAD(Si)
- Low Noise
- Low Offset Voltage..... 2.1mV (Max)
- High Slew Rate1.7V/μs (Min)
- Gain Bandwidth Product8.0MHz (Typ)

Applications

- · High Q, Active Filters
- Voltage Regulators
- Integrators
- Signal Generators
- Voltage References
- Space Environments

Description

The HS-OP470ARH is a radiation hardened, monolithic quad operational amplifier that provides highly reliable performance in harsh radiation environments. Its excellent noise characteristics coupled with an unique array of dynamic specifications make this amplifier well-suited for a variety of satellite system applications. Dielectrically isolated, bipolar processing makes this device immune to Single Event Latch-up.

The HS-OP470ARH shows almost no change in offset voltage after exposure to 100K RAD(Si) gamma radiation, with only a minor increase in current. Complementing these specifications is a post radiation open loop gain in excess of 40kV/V.

This guad operational amplifier is available in an industry standard pinout, allowing for immediate interchangeability with most other quad operational amplifiers.

Specifications for Rad Hard QML devices are controlled by the Defense Supply Center in Columbus (DSCC). SMD numbers must be used when ordering.

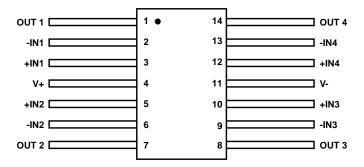
Detailed Electrical Specifications for this are contained in SMD 5962-98533. A "hot-link" is provided on our homepage with instructions for downloading. http://www.intersil.com/data/sm/index.htm

Ordering Information

SMD PART NUMBER	INTERSIL PART NUMBER	TEMP. RANGE (°C)	PACKAGE	CASE OUTLINE
5962R9853301VXC	HS9-OP470ARH-Q	-55 to 125	14 Ld Flatpack	CDFP3-F14
N/A	HS9-OP470ARH/Sample	25	14 Ld Flatpack	CDFP3-F14

Pinout

HS-OP470ARH (FLATPACK) TOP VIEW



HS-OP470ARH

Metallization Mask Layout

DIE DIMENSIONS:

95 mils x 99 mils x 19 mils ± 1 mil (2420 μ m x 2530 μ m x 483 μ m $\pm 25.4 \mu$ m)

METALLIZATION:

Type: AI, 1% Cu Thickness: 16kÅ ±2kÅ

SUBSTRATE POTENTIAL (Powered Up):

Unbiased

BACKSIDE FINISH:

Silicon

PASSIVATION:

Type: Nitride (SI3N4) over Silox (SIO2, 5% Phos.)

Silox Thickness: 12kÅ ±2kÅ Nitride Thickness: 3.5kÅ ±1.5kÅ

WORST CASE CURRENT DENSITY:

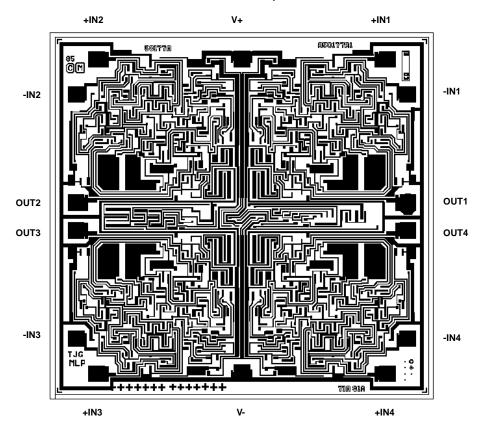
 $<2.0 \times 10^5 \text{ A/cm}^2$

TRANSISTOR COUNT:

175

PROCESS:

Bipolar Dielectric Isolation



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